

LISTING OF CLAIMS

This listing of claims will replace all prior versions, and listings, of claims in the application:

1. (Previously Presented) A method for assessing the probability of transaction success of a business transaction that will interact with one or more software applications in a target computer environment, the method comprising the steps of:
gathering a plurality of defect data items corresponding to the first software application; relative to a specific business transaction in a target computer environment and for each item of the gathered defect data, generating an item-specific predicted business transaction failure rate based on the defect data items;
combining each item-specific predicted business transaction failure rate so as to generate a combined business transaction failure rate within the computer environment; and
generating an output indicating the combined business transaction failure rate within the computer environment.
2. (Original) The method of claim 1, wherein the gathered defect data includes unit test data.
3. (Original) The method of claim 1, wherein the gathered defect data includes functional test data.
4. (Original) The method of claim 1, wherein the gathered defect data includes system test data.
5. (Original) The method of claim 1, wherein the gathered defect data includes translation test data.

6. (Original) The method of claim 1, wherein the gathered defect data includes performance test data.
7. (Original) The method of claim 1, wherein the gathered defect data includes integration test data.
8. (Original) The method of claim 1, further comprising the step of outputting the predicted transaction failure rate.
9. (Previously Presented) A system for assessing the probability of business transaction success that will interact with one or more software applications in a target computer environment, the system comprising:
 - a logic element configured to gatherer a plurality of defect data items corresponding to the first software application;
 - a logic element configured to generate an item-specific predicted business transaction failure rate based on the defect data items relative to a specific business transaction in a target computer environment for each of item of the gathered defect data;
 - a logic element configured to combine each item-specific predicted business transaction failure rate so as to generate a combined business transaction failure rate within the computer environment; and
 - a circuit configured to generate an output that indicates the combined business transaction failure rate within the computer environment.
10. (Original) The system of claim 9, wherein the gathered defect data includes unit test data.
11. (Original) The system of claim 9, wherein the gathered defect data includes functional

test data.

12. (Original) The system of claim 9, wherein the gathered defect data includes system test data.
13. (Original) The system of claim 9, wherein the gathered defect data includes translation test data.
14. (Original) The system of claim 9, wherein the gathered defect data includes performance test data.
15. (Original) The system of claim 9, wherein the gathered defect data includes integration test data.
16. (Original) The system of claim 9, wherein the system further outputs the predicted business transaction failure rate.
17. (Cancelled)